Product data sheet

1. General description

The 74LV00 is a quad 2-input NAND gate. Inputs include clamp diodes. This enables the use of current limiting resistors to interface inputs to voltages in excess V_{CC} .

This product has been qualified to the Automotive Electronics Council (AEC) standard Q100 (Grade 1) and is suitable for use in automotive applications.

2. Features and benefits

- Automotive product qualification in accordance with AEC-Q100 (Grade 1)
 - Specified from -40 °C to +85 °C and from -40 °C to +125 °C
- Wide supply voltage range from 1.0 to 5.5 V
- · CMOS low power dissipation
- Latch-up performance exceeds 100 mA per JESD 78 Class II Level B
- Optimized for low voltage applications: 1.0 V to 3.6 V
- Accepts TTL input levels between V_{CC} = 2.7 V and V_{CC} = 3.6 V
- Typical output ground bounce < 0.8 V at V_{CC} = 3.3 V and T_{amb} = 25 °C
- Typical HIGH-level output voltage (V_{OH}) undershoot: > 2 V at V_{CC} = 3.3 V and T_{amb} = 25 °C
- Complies with JEDEC standards:
 - JESD8-7 (1.65 V to 1.95 V)
 - JESD8-5 (2.3 V to 2.7 V)
 - JESD8C (2.7 V to 3.6 V)
 - JESD36 (4.5 V to 5.5 V)
- ESD protection:
 - HBM: ANSI/ESDA/JEDEC JS-001 class 2 exceeds 2000 V
 - CDM: ANSI/ESDA/JEDEC JS-002 class C3 exceeds 1000 V

3. Ordering information

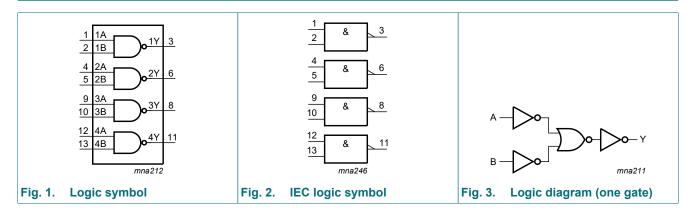
Table 1. Ordering information

Type number	Package	Package Package				
	Temperature range	Name	Name Description			
74LV00D-Q100	-40 °C to +125 °C	SO14	plastic small outline package; 14 leads; body width 3.9 mm	SOT108-1		
74LV00PW-Q100	-40 °C to +125 °C	TSSOP14	plastic thin shrink small outline package; 14 leads; body width 4.4 mm	SOT402-1		



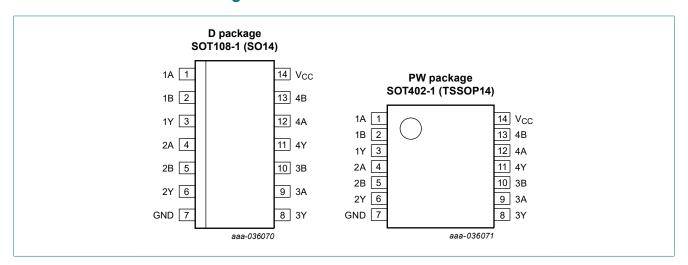
Quad 2-input NAND gate

4. Functional diagram



5. Pinning information

5.1. Pinning



5.2. Pin description

Table 2. Pin description

Symbol	Pin	Description
1A, 2A, 3A, 4A	1, 4, 9, 12	data input
1B, 2B, 3B, 4B	2, 5, 10, 13	data input
1Y, 2Y, 3Y, 4Y	3, 6, 8, 11	data output
GND	7	ground (0 V)
V _{CC}	14	supply voltage

Quad 2-input NAND gate

6. Functional description

Table 3. Function table

 $H = HIGH \ voltage \ level; \ L = LOW \ voltage \ level; \ X = don't \ care$

Input	Output	
nA	nB n	
L	X	Н
X	L	Н
Н	Н	L

7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134). Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Max	Unit
V _{CC}	supply voltage		-0.5	+7.0	V
I _{IK}	input clamping current	$V_1 < -0.5 \text{ V or } V_1 > V_{CC} + 0.5 \text{ V}$ [1]	-	±20	mA
I _{OK}	output clamping current	$V_O < -0.5 \text{ V or } V_O > V_{CC} + 0.5 \text{ V}$ [1]	-	±50	mA
Io	output current	$V_{O} = -0.5 \text{ V to } (V_{CC} + 0.5 \text{ V})$	-	±25	mA
Icc	supply current		-	50	mA
I _{GND}	ground current		-50	-	mA
T _{stg}	storage temperature		-65	+150	°C
P _{tot}	total power dissipation	$T_{amb} = -40 ^{\circ}\text{C to } +125 ^{\circ}\text{C}$ [2]	-	500	mW

^{1]} The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

8. Recommended operating conditions

Table 5. Recommended operating conditions

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{CC}	supply voltage	[1]	1.0	3.3	5.5	V
VI	input voltage		0	-	V _{CC}	V
Vo	output voltage		0	-	V _{CC}	V
T _{amb}	ambient temperature		-40	+25	+125	°C
Δt/ΔV	input transition rise and fall rate	V _{CC} = 1.0 V to 2.0 V	-	-	500	ns/V
		V _{CC} = 2.0 V to 2.7 V	-	-	200	ns/V
		V _{CC} = 2.7 V to 3.6 V	-	-	100	ns/V
		V _{CC} = 3.6 V to 5.5 V	-	-	50	ns/V

^[1] The static characteristics are guaranteed from V_{CC} = 1.2 V to V_{CC} = 5.5 V, but LV devices are guaranteed to function down to V_{CC} = 1.0 V (with input levels GND or V_{CC}).

^[2] For SOT108-1 (SO14) package: P_{tot} derates linearly with 10.1 mW/K above 100 °C. For SOT402-1 (TSSOP14) package: P_{tot} derates linearly with 7.3 mW/K above 81 °C.

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9. Static characteristics

Table 6. Static characteristics

Voltages are referenced to GND (ground = 0 V).

Symbol	pol Parameter Conditions		-40	-40 °C to +85 °C			-40 °C to +125 °C	
			Min	Typ[1]	Max	Min	Max	
V _{IH}	HIGH-level	V _{CC} = 1.2 V	0.9	-	-	0.9	-	V
	input voltage	V _{CC} = 2.0 V	1.4	-	-	1.4	-	V
		V _{CC} = 2.7 V to 3.6 V	2.0	-	-	2.0	-	V
		V _{CC} = 4.5 V to 5.5 V	0.7V _{CC}	-	-	0.7V _{CC}	-	V
V _{IL}	LOW-level	V _{CC} = 1.2 V	-	-	0.3	-	0.3	V
	input voltage	V _{CC} = 2.0 V	-	-	0.6	-	0.6	V
		V _{CC} = 2.7 V to 3.6 V	-	-	0.8	-	0.8	V
		V _{CC} = 4.5 V to 5.5 V	-	-	0.3V _{CC}	-	0.3V _{CC}	V
V _{OH}	HIGH-level	V _I = V _{IH} or V _{IL}						
	output voltage	I _O = -100 μA; V _{CC} = 1.2 V	-	1.2	-	-	-	V
		I _O = -100 μA; V _{CC} = 2.0 V	1.8	2.0	-	1.8	-	V
		I _O = -100 μA; V _{CC} = 2.7 V	2.5	2.7	-	2.5	-	V
		I _O = -100 μA; V _{CC} = 3.0 V	2.8	3.0	-	2.8	-	V
		I _O = -100 μA; V _{CC} = 4.5 V	4.3	4.5	-	4.3	-	V
		I _O = -6 mA; V _{CC} = 3.0 V	2.4	2.82	-	2.2	-	V
		I _O = -12 mA; V _{CC} = 4.5 V	3.6	4.2	-	3.5	-	V
V _{OL}	LOW-level	V _I = V _{IH} or V _{IL}						
	output voltage	I _O = 100 μA; V _{CC} = 1.2 V	-	0	-	-	-	V
		I _O = 100 μA; V _{CC} = 2.0 V	-	0	0.2	-	0.2	V
		I _O = 100 μA; V _{CC} = 2.7 V	-	0	0.2	-	0.2	V
		I _O = 100 μA; V _{CC} = 3.0 V	-	0	0.2	-	0.2	V
		I _O = 100 μA; V _{CC} = 4.5 V	-	0	0.2	-	0.2	V
		I _O = 6 mA; V _{CC} = 3.0 V	-	0.25	0.40	-	0.50	V
		I _O = 12 mA; V _{CC} = 4.5 V	-	0.35	0.55	-	0.65	V
l _l	input leakage current	$V_I = V_{CC}$ or GND; $V_{CC} = 5.5 \text{ V}$	-	-	1.0	-	1.0	μA
I _{CC}	supply current	$V_I = V_{CC}$ or GND; $I_O = 0$ A; $V_{CC} = 5.5$ V	-	-	20.0	-	40	μA
Δl _{CC}	additional supply current	per input; V _I = V _{CC} - 0.6 V; V _{CC} = 2.7 V to 3.6 V	-	-	500	-	850	μA
C _I	input capacitance		-	3.5	-	-	-	pF

^[1] Typical values are measured at T_{amb} = 25 °C.

Quad 2-input NAND gate

10. Dynamic characteristics

Table 7. Dynamic characteristics

GND = 0 V; For test circuit see Fig. 5.

Symbol	Parameter	Conditions		-40	°C to +85	°C	-40 °C to +125 °C		Unit
				Min	Typ[1]	Max	Min	Max	
t _{pd}	propagation delay	nA, nB to nY; see Fig. 4	[2]						
		V _{CC} = 1.2 V		-	45	-	-	-	ns
		V _{CC} = 2.0 V		-	15	26	-	31	ns
		V _{CC} = 2.7 V		-	11	18	-	23	ns
		V _{CC} = 3.0 V to 3.6 V; C _L = 15 pF	[3]	-	7	-	-	-	ns
		V _{CC} = 3.0 V to 3.6 V	[3]	-	9.0	15	-	18	ns
		V _{CC} = 4.5 V to 5.5 V	[3]	-	6.5	11	-	14	ns
C _{PD}	power dissipation capacitance	C_L = 50 pF; f_i = 1 MHz; V_I = GND to V_{CC}	[4]	-	22	-	-	-	pF

- All typical values are measured at T_{amb} = 25 °C.
- t_{pd} is the same as t_{PLH} and t_{PHL} . Typical values are measured at nominal supply voltage (V_{CC} = 3.3 V and V_{CC} = 5.0 V). [3]
- C_{PD} is used to determine the dynamic power dissipation (P_D in μW).

 $P_D = C_{PD} \times V_{CC}^2 \times f_i \times N + \Sigma (C_L \times V_{CC}^2 \times f_o)$ where:

f_i = input frequency in MHz, f_o = output frequency in MHz

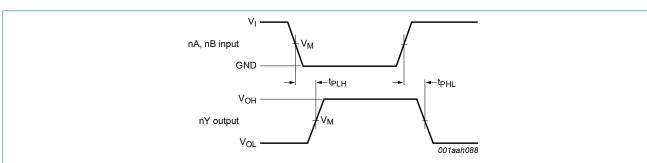
C_L = output load capacitance in pF

V_{CC} = supply voltage in V

N = number of inputs switching

 $\Sigma(C_L \times V_{CC}^2 \times f_0)$ = sum of the outputs.

10.1. Waveform and test circuit



Measurement points are given in Table 8.

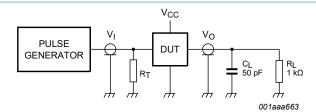
V_{OL} and V_{OH} are typical voltage output levels that occur with the output load.

The input (nA, nB) to output (nY) propagation delays

Table 8. Measurement points

Supply voltage	Input	Output
V _{cc}	V _M	V _M
< 2.7 V	0.5V _{CC}	0.5V _{CC}
2.7 V to 3.6 V	1.5 V	1.5 V
≥ 4.5 V	0.5V _{CC}	0.5V _{CC}

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Test data is given in Table 9.

Definitions test circuit:

 R_{T} = Termination resistance should be equal to output impedance Z_{o} of the pulse generator;

R_L = Load resistance;

 C_L = Load capacitance including jig and probe capacitance.

Fig. 5. Test circuit for measuring switching times

Table 9. Test data

Supply voltage	Input		
V _{CC}	V _I	t _r , t _f	
< 2.7 V	V _{CC}	≤ 2.5 ns	
2.7 V to 3.6 V	2.7 V	≤ 2.5 ns	
≥ 4.5 V	V _{CC}	≤ 2.5 ns	

Quad 2-input NAND gate

11. Package outline

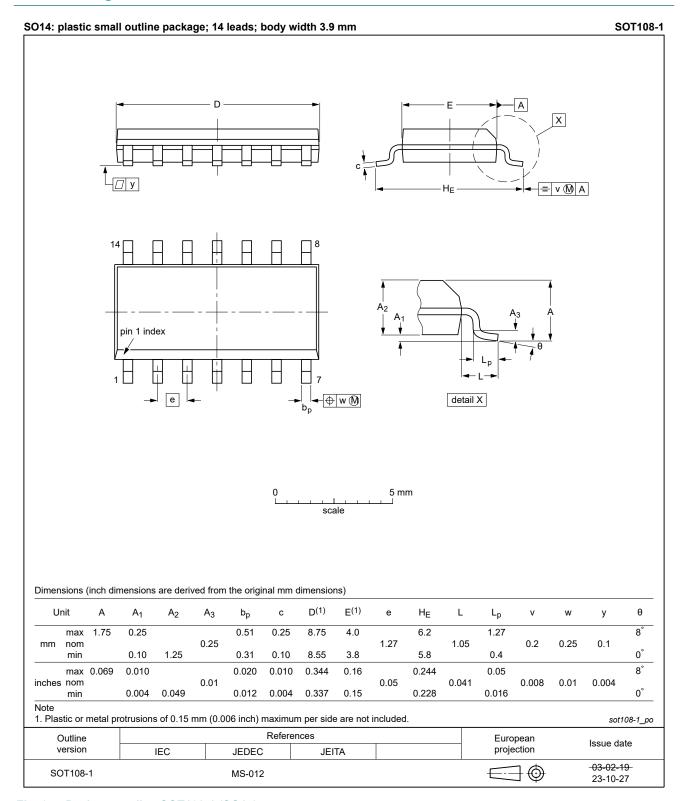


Fig. 6. Package outline SOT108-1 (SO14)

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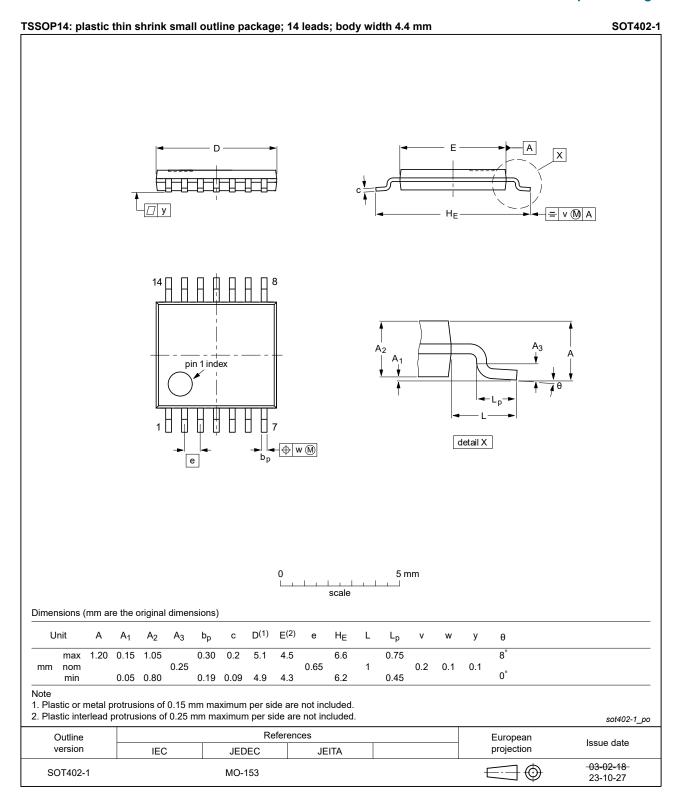


Fig. 7. Package outline SOT402-1 (TSSOP14)

Quad 2-input NAND gate

12. Abbreviations

Table 10. Abbreviations

Acronym	Description	
CDM	Charged Device Model	
CMOS	mplementary Metal Oxide Semiconductor	
DUT	Device Under Test	
ESD	ElectroStatic Discharge	
HBM	Human Body Model	
TTL	ransistor-Transistor Logic	

13. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74LV00_Q100 v.1	20240122	Product data sheet	-	-

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14. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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